# 4-Mbit (512K x 8) Static RAM 

## Features

- Temperature Ranges
- Commercial: $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$
- Industrial: $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$
- Automotive: $-40^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$
- High speed
$-\mathrm{t}_{\mathrm{AA}}=10 \mathrm{~ns}$
- Low active power
- 324 mW (max.)
- 2.0 V data retention
- Automatic power-down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with CE and $\overline{O E}$ features


## Functional Description ${ }^{[1]}$

The CY7C1049CV33 is a high-performance CMOS Static RAM organized as 524,288 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ( $\overline{\mathrm{CE}}$ ), an active LOW Output Enable (OE), and three-state drivers. Writing to the device is accomplished by taking Chip Enable (CE) and Write Enable (WE) inputs LOW. Data on the eight I/O pins $\left(I / O_{0}\right.$ through $\left.I / O_{7}\right)$ is then written into the location specified on the address pins ( $\mathrm{A}_{0}$ through $\mathrm{A}_{18}$ ).
Reading from the device is accomplished by taking Chip Enable (CE) and Output Enable (OE) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.
The eight input/output pins $\left(1 / \mathrm{O}_{0}\right.$ through $\left.\mathrm{I} / \mathrm{O}_{7}\right)$ are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled ( $\overline{\mathrm{OE}}$ HIGH), or during a Write operation (CE LOW, and WE LOW).
The CY7C1049CV33 is available in standard 400-mil-wide 36-pin SOJ package and 44-pin TSOP II package with center power and ground (revolutionary) pinout.


Notes:

1. For guidelines on SRAM system design, please refer to the System Design Guidelines Cypress application note, available on the internet at www.cypress.com.

## Selection Guide

|  |  | $\mathbf{- 8}$ | $\mathbf{- 1 0}$ | $\mathbf{- 1 2}$ | $\mathbf{- 1 5}$ | $\mathbf{- 2 0}$ | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: | :---: | :---: |
| Maximum Access Time |  | 8 | 10 | 12 | 15 | 20 | ns |
| Maximum Operating Current | Commercial | 100 | 90 | 85 | 80 | 80 | mA |
|  | Industrial | 110 | 100 | 95 | 90 | 90 | mA |
|  | Automotive | - | - | - | 95 | - | mA |
| Maximum CMOS Standby Current | Commercial / Industrial | 10 | 10 | 10 | 10 | 10 | mA |
|  | Automotive | - | - | - | 15 | - | mA |

Shaded areas contain advance information.

## Pin Definitions

| Pin Name | 36-SOJ <br> Pin Number | 44 TSOP-II <br> Pin Number | I/O Type | Description |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{A}_{0}-\mathrm{A}_{18}$ | $\begin{gathered} 1-5,14-18, \\ 20-24,32-35 \end{gathered}$ | $\begin{gathered} 3-7,16-20 \\ 26-30,38-41 \end{gathered}$ | Input | Address Inputs used to select one of the address locations. |
| $\mathrm{I} / \mathrm{O}_{0}-\mathrm{l} / \mathrm{O}_{7}$ | $\begin{gathered} 7,8,11,12,25, \\ 26,29,30 \end{gathered}$ | $\begin{aligned} & 9,10,13,14 \\ & 31,32,35,36 \end{aligned}$ | Input/Output | Bidirectional Data I/O lines. Used as input or output lines depending on operation |
| $\mathrm{NC}{ }^{[2]}$ | 19,36 | $\begin{gathered} \hline 1,2,21,22,23 \\ 24,25,42,43 \\ 44 \end{gathered}$ | No Connect | No Connects. This pin is not connected to the die |
| $\overline{\mathrm{WE}}$ | 13 | 15 | Input/Control | Write Enable Input, active LOW. When selected LOW, a WRITE is conducted. When selected HIGH, a READ is conducted. |
| $\overline{\mathrm{CE}}$ | 6 | 8 | Input/Control | Chip Enable Input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip. |
| $\overline{\mathrm{OE}}$ | 31 | 37 | Input/Control | Output Enable, active LOW. Controls the direction of the I/O pins. When LOW, the I/O pins are allowed to behave as outputs. When deasserted HIGH, I/O pins are three-stated, and act as input data pins. |
| $\mathrm{V}_{\text {SS }}$, GND | 10,28 | 12,34 | Ground | Ground for the device. Should be connected to ground of the system. |
| $\mathrm{V}_{\mathrm{CC}}$ | 9,27 | 11,33 | Power Supply | Power Supply inputs to the device. |

## Notes:

2. NC pins are not connected on the die.

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature $\qquad$ $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Ambient Temperature with
Power Applied $\qquad$ $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
Supply Voltage on $\mathrm{V}_{\mathrm{CC}}$ to Relative $\mathrm{GND}^{[3]}-0.5 \mathrm{~V}$ to +4.6 VDC
Voltage Applied to Outputs
in High-Z State ${ }^{[3]}$ $\qquad$ -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$
Electrical Characteristics Over the Operating Range

Input Voltage ${ }^{[3]}$..................................... -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$
Current into Outputs (LOW)......................................... 20 mA
Operating Range

| Range | Ambient Temperature | $\mathbf{V}_{\mathbf{C C}}$ |  |
| :--- | :---: | :---: | :---: |
| Commercial | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | $3.3 \mathrm{~V} \pm 0.3 \mathrm{~V}$ |  |
| Industrial | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |  |  |
| Automotive | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |  |  |


| Parameter | Description | Test Conditions |  | -8 |  | -10 |  | -12 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | Min. | Max. | Min. | Max. | Min. | Max. |  |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\mathrm{V}_{\mathrm{CC}}=$ Min.; $\mathrm{I}_{\mathrm{OH}}=-4$ |  | 2.4 |  | 2.4 |  | 2.4 |  | V |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW Voltage | $\mathrm{V}_{\mathrm{CC}}=\mathrm{Min} .$, ; $\mathrm{I}_{\mathrm{OL}}=8.0$ |  |  | 0.4 |  | 0.4 |  | 0.4 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage |  |  | 2.0 | $\begin{aligned} & \mathrm{V}_{\mathrm{Cc}} \\ & +0.3 \end{aligned}$ | 2.0 | $\begin{aligned} & \hline \mathrm{V}_{\mathrm{CC}} \\ & +0.3 \end{aligned}$ | 2.0 | $\begin{aligned} & \hline \mathrm{V}_{\mathrm{cc}} \\ & +0.3 \end{aligned}$ | V |
| $\mathrm{V}_{\mathrm{IL}}$ | Input LOW Voltage ${ }^{[3]}$ |  |  | -0.3 | 0.8 | -0.3 | 0.8 | -0.3 | 0.8 | V |
| $\mathrm{I}_{1 \times}$ | Input Load Current | $\mathrm{GND} \leq \mathrm{V}_{1} \leq \mathrm{V}_{\mathrm{CC}}$ | Com'/Ind'I | -1 | +1 | -1 | +1 | -1 | +1 | $\mu \mathrm{A}$ |
| ${ }^{\text {IOZ }}$ | Output Leakage Current | $\mathrm{GND} \leq \mathrm{V}_{\mathrm{OUT}} \leq \mathrm{V}_{\mathrm{CC}},$ Output Disabled | Com'//Ind'I | -1 | +1 | -1 | +1 | -1 | +1 | $\mu \mathrm{A}$ |
| ${ }^{\text {cc }}$ | $\mathrm{V}_{\mathrm{CC}}$ Operating Supply Current | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=\text { Max., } \\ & \mathrm{f}=\mathrm{f}_{\mathrm{MAX}}=1 / \mathrm{t}_{\mathrm{RC}} \end{aligned}$ | Com'l |  | 100 |  | 90 |  | 85 | mA |
|  |  |  | Ind'l |  | 110 |  | 100 |  | 95 | mA |
| $\mathrm{I}_{\text {SB1 }}$ | Automatic CE Power-down Current -TTL Inputs | $\begin{aligned} & \text { Max. } V_{\mathrm{CC}}, \overline{\mathrm{CE}} \geq \mathrm{V}_{\mathrm{IH}} ; \\ & \mathrm{V}_{\text {IN }} \geq \mathrm{V}_{\mathrm{IH}} \text { or } \\ & \mathrm{V}_{\text {IN }} \leq \mathrm{V}_{\mathrm{IL}}, f=\mathrm{f}_{\mathrm{MAX}} \end{aligned}$ | Com'//Ind'I |  | 40 |  | 40 |  | 40 | mA |
| ${ }^{\text {SB2 }}$ | Automatic CE Power-down Current -CMOS Inputs | $\begin{aligned} & \text { Max. } V_{C C}, \\ & C E \geq V_{C C}-0.3 V, \\ & V_{I N} \geq V_{C C}-0.3 V, \\ & \text { or } V_{I N} \leq 0.3 V, f=0 \end{aligned}$ | Com'//Ind'I |  | 10 |  | 10 |  | 10 | mA |

Electrical Characteristics Over the Operating Range


## Note

3. $\mathrm{V}_{\mathrm{IL}}($ min. $)=-2.0 \mathrm{~V}$ and $\mathrm{V}_{\mathrm{IH}}(\max )=\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$ for pulse durations of less than 20 ns .

Electrical Characteristics Over the Operating Range (continued)

| Parameter | Description | Test Conditions |  | -15 |  | -20 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | Min. | Max. | Min. | Max. |  |
| $\mathrm{I}_{\text {SB1 }}$ | Automatic CE <br> Power-down Current <br> -TTL Inputs | $\begin{aligned} & \text { Max. } V_{\mathrm{CC}}, \overline{\mathrm{CE}} \geq \mathrm{V}_{\mathrm{IH}} ; \\ & \mathrm{V}_{\mathrm{IN}} \geq \mathrm{V}_{\mathrm{IH}} \text { or } \\ & \mathrm{V}_{\text {IN }} \leq \mathrm{V}_{\mathrm{IL}}, f=\mathrm{f}_{\mathrm{MAX}} \end{aligned}$ | Com'l / Ind'l |  | 40 |  | 40 | mA |
|  |  |  | Automotive |  | 45 |  | - | mA |
| $\mathrm{I}_{\text {SB2 }}$ | Automatic CE Power-down Current -CMOS Inputs | $\begin{aligned} & \text { Max. } V_{C C}, \\ & \overline{C E} \geq V_{C C}-0.3 V, \\ & V_{I N} \geq V_{C C}-0.3 V \\ & \text { or } V_{\text {IN }} \leq 0.3 V, f=0 \end{aligned}$ | Com'//Ind'I |  | 10 |  | 10 | mA |
|  |  |  | Automotive |  | 15 |  | - | mA |

## Thermal Resistance ${ }^{[4]}$

| Parameter | Description | Test Conditions | $\begin{gathered} \text { 36-pin SOJ } \\ \text { (Non Pb-Free) } \end{gathered}$ | $\begin{aligned} & \text { 36-pin SOJ } \\ & \text { (Pb-Free) } \end{aligned}$ | 44-TSOP-II (Non Pb-Free) | 44-TSOP-II (Pb-Free) | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\Theta_{J A}$ | Thermal Resistance (Junction to Ambient) | Test conditions follow standard test methods and procedures for measuring thermal impedance, per EIA / JESD51. | 46.51 | 46.51 | 41.66 | 41.66 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\Theta_{\mathrm{JC}}$ | Thermal Resistance (Junction to Case) |  | 18.8 | 18.8 | 10.56 | 10.56 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

Capacitance ${ }^{[4]}$

| Parameter | Description | Test Conditions | Max. | Unit |
| :--- | :--- | :--- | :--- | :---: |
| $\mathrm{C}_{\mathrm{IN}}$ | Input Capacitance | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{f}=1 \mathrm{MHz}$, | 8 | pF |
| $\mathrm{C}_{\mathrm{OUT}}$ | I/O Capacitance | $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}$ | 8 | pF |

AC Test Loads and Waveforms ${ }^{[5]}$

(a)

(b)

High-Z characteristics:


Rise Time: $1 \mathrm{~V} / \mathrm{ns}$

ALL INPUT PUUSES


(d)

## Notes:

4. Tested initially and after any design or process changes that may affect these parameters.
5. AC characteristics (except High-Z) for all 8-ns and $10-\mathrm{ns}$ parts are tested using the load conditions shown in Figure (a). All other speeds are tested using the Thevenin load shown in Figure (b). High-Z characteristics are tested for all speeds using the test load shown in Figure (d).

AC Switching Characteristics Over the Operating Range ${ }^{[6]}$

| Parameter | Description | -8 |  | -10 |  | -12 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Max. | Min. | Max. | Min. | Max. |  |
| Read Cycle |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {power }}{ }^{[7]}$ | $\mathrm{V}_{\mathrm{CC}}$ (typical) to the first access | 1 |  | 1 |  | 1 |  | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\mathrm{RC}}$ | Read Cycle Time | 8 |  | 10 |  | 12 |  | ns |
| $\mathrm{t}_{\mathrm{AA}}$ | Address to Data Valid |  | 8 |  | 10 |  | 12 | ns |
| $\mathrm{t}_{\mathrm{OHA}}$ | Data Hold from Address Change | 3 |  | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {ACE }}$ | $\overline{\mathrm{CE}}$ LOW to Data Valid |  | 8 |  | 10 |  | 12 | ns |
| $\mathrm{t}_{\text {doe }}$ | $\overline{\mathrm{OE}}$ LOW to Data Valid |  | 4 |  | 5 |  | 6 | ns |
| t Lzoe | $\overline{\text { OE LOW to Low-Z }}$ | 0 |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {Hzoe }}$ | $\overline{\mathrm{OE}}$ HIGH to High-Z ${ }^{[8,9]}$ |  | 4 |  | 5 |  | 6 | ns |
| tlzCe | $\overline{\mathrm{CE}}$ LOW to Low-Z ${ }^{[9]}$ | 3 |  | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {HZCE }}$ | $\overline{\mathrm{CE}}$ HIGH to High-Z ${ }^{[8,9]}$ |  | 4 |  | 5 |  | 6 | ns |
| $\mathrm{t}_{\text {PU }}$ | $\overline{\text { CE }}$ LOW to Power-up | 0 |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {PD }}$ | $\overline{\mathrm{CE}}$ HIGH to Power-down |  | 8 |  | 10 |  | 12 | ns |
| Write Cycle ${ }^{[10,11]}$ |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{wc}}$ | Write Cycle Time | 8 |  | 10 |  | 12 |  | ns |
| $\mathrm{t}_{\text {SCE }}$ | $\overline{\mathrm{CE}}$ LOW to Write End | 6 |  | 7 |  | 8 |  | ns |
| $\mathrm{t}_{\mathrm{AW}}$ | Address Set-up to Write End | 6 |  | 7 |  | 8 |  | ns |
| $\mathrm{t}_{\mathrm{HA}}$ | Address Hold from Write End | 0 |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {SA }}$ | Address Set-up to Write Start | 0 |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {PWE }}$ | $\overline{\text { WE Pulse Width }}$ | 6 |  | 7 |  | 8 |  | ns |
| $\mathrm{t}_{\text {SD }}$ | Data Set-up to Write End | 4 |  | 5 |  | 6 |  | ns |
| $\mathrm{t}_{\mathrm{HD}}$ | Data Hold from Write End | 0 |  | 0 |  | 0 |  | ns |
| tlzwe | $\overline{\text { WE }}$ HIGH to Low-Z ${ }^{[9]}$ | 3 |  | 3 |  | 3 |  | ns |
| thzwe | $\overline{\text { WE }}$ LOW to High-Z ${ }^{[8,9]}$ |  | 4 |  | 5 |  | 6 | ns |

Shaded areas contain advance information.
AC Switching Characteristics Over the Operating Range ${ }^{[6]}$

| Parameter | Description | -15 |  | -20 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Max. | Min. | Max. |  |
| Read Cycle |  |  |  |  |  |  |
| $\mathrm{t}_{\text {power }}{ }^{\text {[7] }}$ | $\mathrm{V}_{\mathrm{Cc}}$ (typical) to the first access | 1 |  | 1 |  | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\mathrm{RC}}$ | Read Cycle Time | 15 |  | 20 |  | ns |
| $\mathrm{t}_{\mathrm{AA}}$ | Address to Data Valid |  | 15 |  | 20 | ns |
| $\mathrm{t}_{\text {OHA }}$ | Data Hold from Address Change |  | 3 |  | 3 | ns |
| $\mathrm{t}_{\text {ACE }}$ | $\overline{\mathrm{CE}}$ LOW to Data Valid |  | 15 |  | 20 | ns |
| $\mathrm{t}_{\text {DOE }}$ | $\overline{\mathrm{OE}}$ LOW to Data Valid |  | 7 |  | 8 | ns |

Notes:
6. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V , input pulse levels of 0 to 3.0 V .
7. $t_{\text {POWER }}$ gives the minimum amount of time that the power supply should be at stable, typical $\mathrm{V}_{\mathrm{CC}}$ values until the first memory access can be performed.
8. $t_{\text {HZOE }}, t_{\text {HZCE }}$, and t $_{\text {HZWE }}$ are specified with a load capacitance of 5 pF as in part (d) of AC Test Loads. Transition is measured $\pm 500 \mathrm{mV}$ from steady-state voltage.
9. At any given temperature and voltage condition, $t_{\text {HZCE }}$ is less than $t_{\text {LZCE }}, t_{H Z O E}$ is less than $t_{\text {ZOE }}$, and $t_{\text {HZWE }}$ is less than $t_{\text {LZWE }}$ for any given device.
10. The internal Write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a Write, and the transition of either of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
11. The minimum Write cycle time for Write Cycle No. 3 ( $\overline{\mathrm{WE}}$ controlled, $\overline{\mathrm{OE}} \mathrm{LOW}$ ) is the sum of $\mathrm{t}_{\mathrm{HZWE}}$ and $\mathrm{t}_{\mathrm{SD}}$.

AC Switching Characteristics Over the Operating Range (continued) ${ }^{[6]}$

| Parameter | Description | -15 |  | -20 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Max. | Min. | Max. |  |
| $\mathrm{t}_{\text {Lzoe }}$ | $\overline{\mathrm{OE}}$ LOW to Low-Z | 0 |  | 0 |  | ns |
| thzoe | $\overline{\mathrm{OE}} \mathrm{HIGH}$ to High-Z ${ }^{[8,9]}$ |  | 7 |  | 8 | ns |
| tlzCe | $\overline{\mathrm{CE}}$ LOW to Low-Z ${ }^{[9]}$ | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {HZCE }}$ | $\overline{\mathrm{CE}}$ HIGH to High-Z ${ }^{[8,9]}$ |  | 7 |  | 8 | ns |
| $\mathrm{t}_{\mathrm{PU}}$ | $\overline{\text { CE }}$ LOW to Power-up | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {PD }}$ | $\overline{\text { CE }}$ HIGH to Power-down |  | 15 |  | 20 | ns |
| Write Cycle ${ }^{[10,11]}$ |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{wc}}$ | Write Cycle Time | 15 |  | 20 |  | ns |
| $\mathrm{t}_{\text {SCE }}$ | $\overline{C E}$ LOW to Write End | 10 |  | 10 |  | ns |
| $\mathrm{t}_{\text {AW }}$ | Address Set-up to Write End | 10 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{HA}}$ | Address Hold from Write End | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {SA }}$ | Address Set-up to Write Start | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {PWE }}$ | $\overline{\text { WE Pulse Width }}$ | 10 |  | 10 |  | ns |
| $\mathrm{t}_{\text {SD }}$ | Data Set-up to Write End | 7 |  | 8 |  | ns |
| $\mathrm{t}_{\mathrm{HD}}$ | Data Hold from Write End | 0 |  | 0 |  | ns |
| t LzWE | $\overline{\text { WE }}$ HIGH to Low-Z ${ }^{[9]}$ | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {HZWE }}$ | $\overline{\text { WE }}$ LOW to High-Z ${ }^{[8, ~ 9]}$ |  | 7 |  | 8 | ns |

## Switching Waveforms

Read Cycle No. ${ }^{[12,13]}$


Notes:
12. Device is continuously selected. $\mathrm{OE}, \mathrm{CE}=\mathrm{V}_{\mathrm{IL}}$. 13. WE is HIGH for Read cycle.

## Switching Waveforms (continued)

Read Cycle No. 2 ( $\overline{\mathrm{OE}}$ Controlled) ${ }^{[13,14]}$


Write Cycle No. 1( $\overline{\text { WE }}$ Controlled, $\overline{\mathrm{OE}}$ HIGH During Write) ${ }^{[15,16]}$


Notes:
14. Address valid prior to or coincident with $\overline{\mathrm{CE}}$ transition LOW.
15. Data $\mathrm{I} / \mathrm{O}$ is high-impedance if $\overline{\mathrm{OE}}=\mathrm{V}_{I H}$.
16. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.
17. During this period the I/Os are in the output state and input signals should not be applied.

## Switching Waveforms (continued)

Write Cycle No. 2 ( $\overline{\mathrm{WE}}$ Controlled, $\overline{\mathrm{OE}}$ LOW) ${ }^{[16]}$


## Truth Table

| CE | OE | WE | $1 / \mathrm{O}_{0}-1 / \mathrm{O}_{7}$ | Mode | Power |
| :---: | :---: | :---: | :---: | :---: | :---: |
| H | X | X | High-Z | Power-down | Standby ( $\mathrm{I}_{\text {SB }}$ ) |
| L | L | H | Data Out | Read | Active ( $\mathrm{I}_{\mathrm{CC}}$ ) |
| L | X | L | Data In | Write | Active ( $\mathrm{I}_{\mathrm{cc}}$ ) |
| L | H | H | High-Z | Selected, Outputs Disabled | Active ( $\mathrm{I}_{\mathrm{cc}}$ ) |

## Ordering Information

| $\begin{gathered} \text { Speed } \\ \text { (ns) } \end{gathered}$ | Ordering Code | Package Name | Package Type | Operating Range |
| :---: | :---: | :---: | :---: | :---: |
| 10 | CY7C1049CV33-10VC | V36 | 36-lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1049CV33-10ZC | Z44 | 44-pin TSOP II |  |
|  | CY7C1049CV33-10VI | V36 | 36-lead (400-Mil) Molded SOJ | Industrial |
|  | CY7C1049CV33-10ZI | Z44 | 44-pin TSOP II |  |
| 12 | CY7C1049CV33-12VC | V36 | 36-lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1049CV33-12ZC | Z44 | 44-pin TSOP II |  |
|  | CY7C1049CV33-12VI | V36 | 36-lead (400-Mil) Molded SOJ | Industrial |
|  | CY7C1049CV33-12ZI | Z44 | 44-pin TSOP II |  |
| 15 | CY7C1049CV33-15VC | V36 | 36-lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1049CV33-15ZC | Z44 | 44-pin TSOP II |  |
|  | CY7C1049CV33-15VI | V36 | 36-lead (400-Mil) Molded SOJ | Industrial |
|  | CY7C1049CV33-15ZI | Z44 | 44-pin TSOP II |  |
|  | CY7C1049CV33-15VE | V36 | 36-lead (400-Mil) Molded SOJ | Automotive |
|  | CY7C1049CV33-15ZSE | Z44 | 44-pin TSOP II |  |
| 20 | CY7C1049CV33-20VC | V36 | 36-lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1049CV33-20VI | V36 | 36-lead (400-Mil) Molded SOJ | Industrial |
| 10 | CY7C1049CV33-10VXC | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Commercial |
|  | CY7C1049CV33-10ZXC | Z44 | 44-pin TSOP II (Pb-Free) |  |
|  | CY7C1049CV33-10VXI | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Industrial |
|  | CY7C1049CV33-10ZXI | Z44 | 44-pin TSOP II (Pb-Free) | Industrial |
| 12 | CY7C1049CV33-12VXC | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Commercial |
|  | CY7C1049CV33-12ZXC | Z44 | 44-pin TSOP II (Pb-Free) |  |
|  | CY7C1049CV33-12VXI | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Industrial |
|  | CY7C1049CV33-12ZXI | Z44 | 44-pin TSOP II (Pb-Free) |  |
| 15 | CY7C1049CV33-15VXC | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Commercial |
|  | CY7C1049CV33-15ZXC | Z44 | 44-pin TSOP II (Pb-Free) |  |
|  | CY7C1049CV33-15VXI | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Industrial |
|  | CY7C1049CV33-15ZXI | Z44 | 44-pin TSOP II (Pb-Free) |  |
|  | CY7C1049CV33-15VXE | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Automotive |
|  | CY7C1049CV33-15ZSXE | Z44 | 44-pin TSOP II | Automotive |
| 20 | CY7C1049CV33-20VXC | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Commercial |
|  | CY7C1049CV33-20VXI | V36 | 36-lead (400-Mil) Molded SOJ (Pb-Free) | Industrial |

Shaded areas contain advance information. Please contact your local Cypress Sales representative for availability of these parts.

CY7C1049CV33

Package Diagrams

## 36-Lead (400-Mil) Molded SOJ V36



DIMENSIUNS IN INCHES MIN.
MAX

| DIM. A |  |
| :---: | :---: |
| ANAM | C.SPI |
| $\frac{.086}{.09 .0}$ | $\frac{.095}{.115}$ |



IDP VJEW
BLTTDM VIEW


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## Document History Page

## Document Title: CY7C1049CV33 4-Mbit (512K x 8) Static RAM

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| REV. | ECN NO. | Issue Date | Orig. of <br> Change | Description of Change |
| :---: | :---: | :---: | :---: | :--- |
| ${ }^{* *}$ | 112569 | $03 / 06 / 02$ | HGK | New data sheet |
| ${ }^{*}$ A | 114091 | $04 / 25 / 02$ | DFP | Changed Tpower unit from ns to $\mu \mathrm{s}$ |
| ${ }^{*} \mathrm{~B}$ | 116479 | $09 / 16 / 02$ | CEA | Add applications foot note to data sheet, page 1. |
| ${ }^{*} \mathrm{C}$ | 262949 | See ECN | RKF | Added Automotive Specs <br> Added $\Theta_{\text {JA }}$ and $\Theta_{\text {JC values on Page \#3. }}$ |
| *D | 300091 | See ECN | RKF | Added -20-ns Speed bin |
| ${ }^{* E}$ | 344595 | See ECN | SYT | Added Pb-Free package on page \#8 <br> Removed shading for CY7C1049CV33-15ZSXE in the ordering Information <br> on page 9 |

